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(c) 2002 American Institute of Physics  
File 99:Wilson Appl. Sci & Tech Abs 1983-2002/Jul  
(c) 2002 The HW Wilson Co.

**DIALOG**  
**Text Abstract Files**

Set	Items	Description
S1	3	AU='TSUKADA, T'
S2	593	AU='TSUKADA, T.'
S3	1	AU='TSUKADA, TSUNEHIRO'
S4	1107	AU='TSUKADA T'
S5	6	AU='TSUKADA TSUNEHIRO'
S6	1652	S1:S5
S7	403925	(DATA OR INFORMATION) (5N) (TRANSMIT? OR TRANSMIS? OR SEND? - OR SENT OR TRANSFER? OR EXCHANG? OR RECEIPT? OR RECEIV?)
S8	2030159	(DISPLAY? OR VIEW?)
S9	0	S6 AND (S7 AND S8)
S10	106	S6 AND (S7 OR S8)
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S16	44	S14 AND (S7 OR S8)
S17	1	S16 AND S11
S18	1	S17 NOT S13

13/3,K/1 (Item 1 from file: 8)  
DIALOG(R)File 8:Ei Compendex(R)  
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05193041 E.I. No: EIP98124512912

**Title: Gesture and facial expression on tele-robotics**

Author: Ohba, K.; Clary, G.; Hiratuka, S.; \*\*Tsukada, T.\*\*; Kotoku, T.;  
Tanie, K.

Corporate Source: MEL, Tsukuba, Jpn

Conference Title: Proceedings of the 1998 IEEE/RSJ International  
Conference on Intelligent Robots and Systems. Part 3 (of 3)

Conference Location: Victoria, Can Conference Date: 19981013-19981017

E.I. Conference No.: 49406

Source: Innovations in Theory, Practice and Applications IEEE  
International Conference on Intelligent Robots and Systems v 3 1998. IEEE,  
Piscataway, NJ, USA, 98CH36190. p 1596-1601

Publication Year: 1998

CODEN: 85RBAH

Language: English

Author: Ohba, K.; Clary, G.; Hiratuka, S.; \*\*Tsukada, T.\*\*; Kotoku, T.;  
Tanie, K.

...Abstract: a most significant factor in tele-communications, such as  
tele-services. To realize the real \*\*time\*\* facial expression  
transportation system, we proposed the facial expression space (FES) and a  
correspondence technique between each personal facial expression spaces.  
Then, real \*\*time\*\* facial expression transportation system is developed,  
which transport the facial expression but not the image itself. This final  
system is able to \*\*display\*\* the same facial expressions in another  
persons, further more in cartoon characters. The experimental results...

Descriptors: Robotics; Telecommunication services; Real \*\*time\*\* systems

13/3,K/2 (Item 1 from file: 65)  
DIALOG(R)File 65:Inside Conferences  
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01895335 INSIDE CONFERENCE ITEM ID: CN019594582

**Essential points for precise etching processes in pulse-\*\*time\*\*-modulated  
ultrahigh-frequency plasma**

Samukawa, S.; \*\*Tsukada, T.\*\*

CONFERENCE: American Vacuum Society-National symposium; 43rd

JOURNAL OF VACUUM SCIENCE AND TECHNOLOGY A VACUUMS SURFACES AND FILMS,  
1997; VOL 15; NUMBER 3/PT1 P: 643-646

American Institute of Physics, 1997

ISSN: 0734-2101

LANGUAGE: English DOCUMENT TYPE: Conference Selected papers

CONFERENCE SPONSOR: American Vacuum Society

CONFERENCE LOCATION: Philadelphia, PA

CONFERENCE DATE: Oct 1996 (199610) (199610)

NOTE:

Also contains papers from three Topical conferences entitled " Flat  
panel \*\*displays\*\*", "Micromechanical systems (MEMS)" and "Magnetic  
surfaces and interfaces" which were also held during the same period;  
See also 4362.0654 vol 22 no 10 1997 for selected abstracts

**Essential points for precise etching processes in pulse-\*\*time\*\*-modulated  
ultrahigh-frequency plasma**

Samukawa, S.; \*\*Tsukada, T.\*\*

NOTE:

Also contains papers from three Topical conferences entitled " Flat  
panel \*\*displays\*\*", "Micromechanical systems (MEMS)" and "Magnetic  
surfaces and interfaces" which were also held during the same...

13/3,K/3 (Item 1 from file: 2)  
DIALOG(R)File 2:INSPEC

(c) 2002 Institution of Electrical Engineers. All rts. reserv.

5920439 INSPEC Abstract Number: B9806-6140C-609, C9806-1250-295

**Title: Facial expression space for smooth tele-communications**

Author(s): Ohba, K.; \*\*Tsukada, T.\*\*; Kotoku, T.; Tanie, K.

Author Affiliation: Mech. Eng. Lab., AIST, Tsukuba, Japan

Conference Title: Proceedings Third IEEE International Conference on Automatic Face and Gesture Recognition (Cat. No.98EX107) p.378-83

Publisher: IEEE Comput. Soc, Los Alamitos, CA, USA

Publication Date: 1998 Country of Publication: USA xvi+625 pp.

ISBN: 0 8186 8344 9 Material Identity Number: XX98-00945

U.S. Copyright Clearance Center Code: 0 8186 8344 9/98/\$10.00

Conference Title: Proceedings Third IEEE International Conference on Automatic Face and Gesture Recognition

Conference Sponsor: IEEE Comput. Soc. Tech. Committee on Pattern Anal. & Machine Intelligence (PAMI); Inf. Process. Soc. Japan (IPSJ); IEICE of Japan; Inst. Image Inf. & Telev. Eng. (ITE); Soc. Instrum. & Control Eng. (SICE)

Conference Date: 14-16 April 1998 Conference Location: Nara, Japan

Language: English

Subfile: B C

Copyright 1998, IEE

Author(s): Ohba, K.; \*\*Tsukada, T.\*\*; Kotoku, T.; Tanie, K.

...Abstract: the most significant factor in tele-communications, such as tele-services. To realize the real \*\*time\*\* facial expression transportation system, we propose the facial expression space (FES) and a correspondence technique between each personal facial expression spaces. Then, real \*\*time\*\* facial expression transportation system is developed, which transports the facial expression but not the image itself. This final system is able to \*\*display\*\* the same facial expressions in another person and further more in cartoon characters. The experimental...

**13/3,K/4 (Item 2 from file: 2)**

DIALOG(R)File 2:INSPEC

(c) 2002 Institution of Electrical Engineers. All rts. reserv.

5818707 INSPEC Abstract Number: B9803-7260-033

**Title: Scaling theory of liquid-crystal \*\*displays\*\* addressed by thin-film transistors**

Author(s): \*\*Tsukada, T.\*\*

Author Affiliation: Central Res. Lab., Hitachi Ltd., Tokyo, Japan

Journal: IEEE Transactions on Electron Devices vol.45, no.2 p. 387-93

Publisher: IEEE,

Publication Date: Feb. 1998 Country of Publication: USA

CODEN: IETDAI ISSN: 0018-9383

SICI: 0018-9383(199802)45:2L.387:STLC;1-2

Material Identity Number: I037-98002

U.S. Copyright Clearance Center Code: 0018-9383/98/\$10.00

Language: English

Subfile: B

Copyright 1998, IEE

**Title: Scaling theory of liquid-crystal \*\*displays\*\* addressed by thin-film transistors**

Author(s): \*\*Tsukada, T.\*\*

Abstract: The proposed scaling theory for designing thin-film transistor/liquid-crystal \*\*displays\*\* (TFT/LCD's) addresses the need for a new design theory for fabricating TFT panels...

... capacitance in the pixels. The trade-off in this scheme is between a short charging-\*\*time\*\* constant and a large aperture ratio, and a large voltage offset and a short discharging-\*\*time\*\* constant. The scaling theory is shown to be a valuable tool to design the next...

...Descriptors: flat panel \*\*displays\*\*; ...

...liquid crystal \*\*displays\*\*;

...Identifiers: liquid-crystal \*\*displays\*\*; ...  
...discharging-\*\*time\*\* constant

**13/3,K/5 (Item 3 from file: 2)**

DIALOG(R)File 2:INSPEC  
(c) 2002 Institution of Electrical Engineers. All rts. reserv.

04133438 INSPEC Abstract Number: B9206-2560R-010

**Title: Threshold voltage shift of amorphous silicon thin-film transistors during pulse operation**

Author(s): Oritsuki, R.; Horii, T.; Sasano, A.; Tsutsui, K.; Koizumi, T.; Kaneko, Y.; \*\*Tsukada, T.\*\*

Author Affiliation: Mbara Works, Hitachi Ltd., Chiba, Japan

Journal: Japanese Journal of Applied Physics, Part 1 (Regular Papers & Short Notes) vol.30, no.12B p.3719-23

Publication Date: Dec. 1991 Country of Publication: Japan

CODEN: JAPNDE ISSN: 0021-4922

Language: English

Subfile: B

Author(s): Oritsuki, R.; Horii, T.; Sasano, A.; Tsutsui, K.; Koizumi, T.; Kaneko, Y.; \*\*Tsukada, T.\*\*

...Abstract: shift of amorphous silicon thin film transistors (TFTs) under pulse operation is discussed. The stress \*\*time\*\*, stress voltage, duty ratio and frequency dependence of the shift have been measured. A positive...

...Descriptors: liquid crystal \*\*displays\*\*;

...Identifiers: stress \*\*time\*\*;

**13/3,K/6 (Item 4 from file: 2)**

DIALOG(R)File 2:INSPEC  
(c) 2002 Institution of Electrical Engineers. All rts. reserv.

03606048 INSPEC Abstract Number: B90032156

**Title: Analysis and design of a-Si TFT/LCD panels with a pixel model**

Author(s): Kaneko, Y.; Sasano, A.; \*\*Tsukada, T.\*\*

Author Affiliation: Hitachi Ltd., Tokyo, Japan

Journal: IEEE Transactions on Electron Devices vol.36, no.12 p. 2953-8

Publication Date: Dec. 1989 Country of Publication: USA

CODEN: IETDAI ISSN: 0018-9383

U.S. Copyright Clearance Center Code: 0018-9383/89/1200-2953\$01.00

Language: English

Subfile: B

Author(s): Kaneko, Y.; Sasano, A.; \*\*Tsukada, T.\*\*

Abstract: The design of a-Si thin-film-transistor/liquid-crystal-\*\*display\*\* (TFT/LCD) panels using a pixel model which consists of an equivalent electrical circuit and...

... used to obtain an analytical expression for pixel electrode voltage during the TFT turn-on \*\*time\*\*. The calculated dependence of the LCD panel transmittance on signal voltage is shown to reproduce...

... TFT-addressed 5-in.-diagonal liquid-crystal color TV has been developed which exhibits excellent \*\*display\*\* quality.

...Descriptors: flat panel \*\*displays\*\*; ...

...liquid crystal \*\*displays\*\*;

...Identifiers: thin film transistor-liquid crystal \*\*display\*\* panel...

...flat panel \*\*display\*\*; ...

...\*\*display\*\* quality

13/3,K/7 (Item 1 from file: 94)

DIALOG(R)File 94:JICST-EPlus

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03852101 JICST ACCESSION NUMBER: 99A0079876 FILE SEGMENT: JICST-E

**Facial Expression Transportation for real-\*\*time\*\* applications.**

CLARY G (1); OHBA K (1); \*\*TSUKADA T\*\* (1); KOTOKU T (1); TANIE K (1)

(1) Aist, Tsukuba, Jpn

Nippon Robotto Gakkai Gakujutsu Koenkai Yokoshu, 1998,

VOL.16th,dai2bunsatsu, PAGE.723-724, FIG.3, REF.2

JOURNAL NUMBER: X0008AAR

UNIVERSAL DECIMAL CLASSIFICATION: 681.51:007.51

LANGUAGE: English COUNTRY OF PUBLICATION: Japan

DOCUMENT TYPE: Conference Proceeding

ARTICLE TYPE: Short Communication

MEDIA TYPE: Printed Publication

**Facial Expression Transportation for real-\*\*time\*\* applications.**

CLARY G (1); OHBA K (1); \*\*TSUKADA T\*\* (1); KOTOKU T (1); TANIE K (1)

...ABSTRACT: with virtual faces is mainly focused to realize smooth tele-communication. To realize the real-\*\*time\*\* facial expression transportation system, a Facial Expression Space (FES), which come directly from the Principal...

...from parameters of VRML face, has been proposed. The goal in this transportation is to \*\*send\*\* through the network the \*\*information\*\* about facial expression, not the images themselves. Then, the final system is able to synthesize...

13/3,K/8 (Item 2 from file: 94)

DIALOG(R)File 94:JICST-EPlus

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02618449 JICST ACCESSION NUMBER: 95A0871838 FILE SEGMENT: JICST-E

**Correction of Specimen Orientation in Three-Dimensional Measurement of Surface Roughness with Small Waviness by Contact Stylus Instrument. 1st Report. Theoretical Foundation.**

CHO N (1); \*\*TSUKADA T\*\* (1); TAKAHASHI M (1)

(1) Tokyo Inst. Technol., Tokyo

Int J Jpn Soc Precis Eng, 1995, VOL.29,NO.2, PAGE.156-161, FIG.9, TBL.1, REF.11

JOURNAL NUMBER: Z0715ABZ ISSN NO: 0916-782X

UNIVERSAL DECIMAL CLASSIFICATION: 531.71/.74

LANGUAGE: English COUNTRY OF PUBLICATION: Japan

DOCUMENT TYPE: Journal

ARTICLE TYPE: Original paper

MEDIA TYPE: Printed Publication

CHO N (1); \*\*TSUKADA T\*\* (1); TAKAHASHI M (1)

...ABSTRACT: used.2) Two parallel measurement lines are used.1) The former is developed with a \*\*view\*\* to measuring the uniform surface.2) The latter is developed with a \*\*view\*\* to measuring the nonuniform surface. The algorithm to decide the optimum measurement length is also developed, and the measurement \*\*time\*\* is reduced.

13/3,K/9 (Item 1 from file: 6)

DIALOG(R)File 6:NTIS

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1824400 NTIS Accession Number: DE94737938

**Development of JAERI material performance database (JMPD) and examples of its utilization**

Tsuji, H. ; Yokoyama, N. ; \*\*Tsukada, T. \*\*; Nakajima, H.

Japan Atomic Energy Research Inst., Tokyo.

Corp. Source Codes: 014802000; 3413000

Report No.: JAERI-M-93-204

Oct 93 31p

Languages: English

Journal Announcement: GRAI9421; NSA1900

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NTIS Prices: PC A03/MF A01

Tsuji, H. ; Yokoyama, N. ; \*\*Tsukada, T. \*\*; Nakajima, H.

...examples of its utilization. The JMPD has been developed since 1986 in JAERI with a \*\*view\*\* to utilizing various kinds of characteristic data of nuclear materials efficiently. Management system of relational...

... K-constant type tests. (3) The method of determining the minimum creep rate and the \*\*time\*\* to onset of the tertiary creep objectively was proposed using creep curve data of high...

18/3,K/1 (Item 1 from file: 233)  
DIALOG(R)File 233:Internet & Personal Comp. Abs.  
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00357434 94CO08-003

**Canon BJC-600**

Harrel, William

COMPUTE , August 1, 1994 , v16 n8 p15-16, 26, 3 Page(s)

ISSN: 0194-357X

Company Name: \*\*Canon\*\*

Product Name: Canon BJC-600

Company Name: \*\*Canon\*\*

... transparency test was somewhat slow, but worth the wait. Comments that it takes a long \*\*time\*\* for the printer driver to rasterize (process) the \*\*data\*\* and \*\*send\*\* it to the printer--up to two or three times longer than similar printers reviewed...